

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN#20141119000A Qualification of Alternate Assembly/Test Sites for Selected devices in the TSSOP Package Change Notification / Sample Request

Dear Customer:

Revision A is to update the BOM differences as a result of adding ASESH as an additional assembly site for the listed devices in Group 1.

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN_ww_admin_team@list.ti.com).

Sincerely,

PCN Team SC Business Services

PCN# 20141119000A Attachment: 1

Products Affected:

According to our records, there are the affected device(s) that you have purchased within the past twenty-four (24) months. Technical details of this Product Change follow on the next page(s).

PCN Number:			20141119000A PCN Date: 01/20/201							01/20/2015
Titl	Title: Qualification of ASE Shanghai as an alternate Assembly/Test Site for Selected devices in the TSSOP Package									
Customer Contact:			PCN Manager		Phone			Dept: Quality Services		
Pro	pose	ed 1 st Ship Da	ite:	03/03/2015	Estir	nated Samp	ole Avai	ability:	Prov Requ	rided upon uest
Cha	ange	Type:		•						
\boxtimes		embly Site		Assembly	Process		X Ass	sembly Ma	teria	ls
	Desi	gn		Electrical				chanical S	pecif	ication
\boxtimes	Test	Site		Packing/S	hipping/	abeling	☐ Tes	st Process		
		er Bump Site		Wafer Bur	_			fer Bump		
	Wafe	er Fab Site		Wafer Fab			U Wa	fer Fab Pr	oces	S
				Part numb						
					PCN D	etails				
Des	script	tion of Chang	je:							
Revision A is to update the BOM differences as a result of adding ASEH as an additional assembly site for the listed devices in Group 1. ASESH will be manufacturing devices with Matte Sn lead finish. These modifications are highlighted and bolded below. Texas Instruments is pleased to announce the qualification of ASE Shanghai (ASES) as an alternate Assembly and Test site for the devices listed below in Group 1 and TI Taiwan (TAI) as an additional Assembly site for the devices in Group 2. Group 2 devices will have identical BOMs between the 2 sites. For group 1, BOM differences are noted in the table below:										
	between the 2 sites. For group 1, bow differences are noted in the table below.									
		What MLA AP1 ASESH								
		at I Compound		MLA 4206193		AP1 SID# 1013		SID		2000508
	Mold Moui	Compound Compound		4206193 4042500		SID# 1013	06338	SID	#EN2 #EY1	2000508
	Mold Moui	l Compound		4206193		SID# 1013	06338	SID	#EN2 #EY1	2000508
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tes Upo <u>nui</u> Exa	Moud Lead t cove t MQ. on examber ample	I Compound Ind Compound Id Finish Perage, insertice Epiry of this For example Custom (Standa) TI can	er or satis	4206193 4042500 NiPdAu onditions will on the combination of the com	ounits of per Recorder in liPdAu for latte Sr	SID# 1013 SID#1013 NiPd# onsistent wir free solution hip with both AM26C311 el). n one of the inish. finish and 1 reel	06338 Au th curren ons in a oth Matt	t testing a single sfee Sn and th 2500 ing ways	#EN2 #EY1 Matt and v anda NiPo	2000508 1000063 e Sn erified with ard part dAu/Ag.
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Changes to product identification re	sulting from this PCN:					
Assembly Site						
Amkor Philippines	Assembly Site Origin (22L)	ASO: AKR				
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA				
TI Taiwan	Assembly Site Origin (22L)	ASO: TAI				
ASE Shanghai	Assembly Site Origin (22L)	ASO: ASH				
Sample product shipping label (not act	ual product label)					
TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 29: MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 LBL: 5A (L) T0: 1750	(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$12 (P) (2P) REV: (V) 0033317 (20L) C\$0: SHE (21L) CC0: U\$A (22L) A\$0: MLA (23L) ACO: MY\$					
Topside Device marking:	C. L. WILL					
Assembly site code for AKR= 4 Assembly site code for MLA= K	G4 = NiPdAu G3= MATTE Sn					
Assembly site code for TAI = T	OJ- WATTE SII					
Assembly site code for ASH= A						

Product Affected

Qualification Group #1 Devices (ASESH assembly):

	AM26C31IPWR	MAX3232IPWR	SN74HC125PWR	SN74HC32PWR
	CD4066BPWR	SN74ACT08PWR	SN74HC138PWR	SN74HC595PWR
l	CD4069UBPWR	SN74AHCT125PWR	SN74HC14PWR	SN74HCT04PWR
l	CD4541BPWR	SN74HC00PWR	SN74HC164PWR	SN74HCT138PWR
	CD74HC123PWR	SN74HC02PWR	SN74HC166PWR	SN74HCT14PWR
l	LM239PWR	SN74HC04PWR	SN74HC174PWR	SN74HCT32PWR
I	LM339APWR	SN74HC05PWR	SN74HC259PWR	SN74HCU04PWR
I	MAX232ECPWR	SN74HC08PWR		

Qualification Group #2 Devices (TAI assembly):

DRV8833PWP DRV8833PWPR

Qualification Group #1 Data:

Qualification Report

MAX232ECPWR Qual (ASESH 14 and 16 pins TSSOP Offload) Approved 09/22/2014

Attributes	Qual Device: MAX232ECPWR	QBS Package: RC4558PWR	QB S Package: SN74LV14APWR	QBS Package: SN74LVC14APWR	QBS Package: ULN2003APW	QBS Package: LMV324IPWR	QBS Package: SN74AHC595PWR	QBS Package: SN74CBT3306PWR	QB S Package: SN74CBTLV3245APWR
Assembly Site	ASESH	ASE SHANGHAI	ASESH	ASE-SH	ASESH	ASE SHANGHAI	ASE SHANGHAI	ASE SHANGHAI	ASE SHANGHAI
Package Family	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	DFAB	SFAB	SFAB	FFAB	SFAB	FFAB	SFAB	SFAB	FFAB
Wafer Fab Process	LBC3S	JI-SLM	EPIC1-S_SLM	P-9750 TLM	JI-SLM	BCB	EPIC1S DLM	50C24X2	ASL3C

Qualification Results

				Da	ta Displayed as: Number	of lots / Total sample :	size / Total failed			
Туре	Test Name / Condition	Duration	QBS Package: RC4558PWR	QBS Package: SN74LV14APWR	QBS Package: SN74LVC14APWR	QBS Package: ULN2003APW	QBS Package: LMV324IPWR	QBS Package: SN74AHC595PWR	QBS Package: SN74CBT3306PWR	QBS Package: SN74CBTLV3245APWR
HAST	Biased HAST, 130C/85%RH	96 Hours	1/77/0	1/77/0	1/77/0	1/77/0	2/158/0	1/77/0	1/77/0	1/77/0
тнв	Temperature Humidity Bias 85C/85%RH	1000 Cycles	-	-	-	-	-	-	-	-
AC	Autoclave 121C	96 Hours	-	-	-	-	-			
UHAST	Unbiased HAST 130C/85%RH	96 Hours	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0
TC	Temperature Cycle, - 65/150C	500 Cycles	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0
HTSL	High Temp. Storage Bake 170C	420 Hours	-	-	-	-	1/77/0	1/77/0	1/77/0	1/77/0
HTSL	High Temp. Storage Bake 150C	1000 Hours	1/77/0	1/77/0	1/77/0	1/77/0	-	-	-	-
HTOL	Life Test, 150C	300 hours	1/77/0	1/77/0	1/77/0	1/77/0	2/164/0	1/77/0	1/77/0	1/77/0
WBS	Ball Bond Shear	Wires	-	-	-	-	-	-	-	-
WBP	Bond Pull	Wires	-	-	-	-	-		-	
PD	Physical Dimensions	-		-		-	-			
HBM	ESD - HBM	1000 V	-	-		-	-			-
CDM	ESD - CDM	250 V	-		-	-	-		-	
LU	CMOS Latchup	(per JESD78 class II)	-	-	-	-	-	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	Pass	Pass	Pass	Pass	Pass
	Bond Strength	Wires	1/76/0	1/76/0	1/76/0	1/76/0	2/160/0	1/77/0	1/77/0	1/77/0

⁻ Preconationing was performed for Autoclave, Unbiased HAST, THB/Blased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTDL options based on an activation energy of 0.7eV: 1320/Tk Hours, 140C/480 Hours, 180C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 159C/Tk Hours, and 170C/420 Hours
- The following are equivalent HTDL options based on an activation energy of 0.7eV: 159C/Tk Hours, and 170C/420 Hours
- The following are equivalent HTDL options port of the property of the Part of the

Notes: **Tests require preconditioning sequence: MSL1-260C

Qualification Group #2 Data:

Reference Qualification Data: Approved April 2012 This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications. Qualification Device: DRV8812A1PWP (MSL1-260C) **Package Construction Details** Assembly Site: Mold Compound: 4205443 TAI A/T # Pins-Designator, Family: 28-PWP, TSSOP Mount Compound: 4208458 Lead Frame Material/Finish: Cu, NiPdAu Bond Wire: 1.3 Mil Dia., Cu Qualification: Plan Test Results Conditions Reliability Test Sample Size / Fail **Electrical Characterization** Per Datasheet Limits **Pass** **Autoclave 121C 77/0 121C, 2 atm (96 Hrs) **T/C -65C/150C 77/0 -65C/+150C (500 Cyc) 500V, 1000V, 1500V 3/0 **ESD HBM** 3/0 ESD CDM 200V, 500V (per JESD78) 6/0 Latch-up

OBS: Qual By Similarity
 Qual Device MAX232ECPWR is qualified at LEVEL1-260C

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com